Stats 300b: Theory of Statistics

Winter 2019

Lecture 12 – February 14

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Warning: these notes may contain factual errors

Reading: HDP Ch.8, VdV 18-19

Outline:

- Uniform Entropy Bounds
 - VC Classes

VC Function Classes

• Chaining

Entropy Integrals Sub-Gaussian Processes

Recap: VC Classes of Sets

Definition 0.1. Given C a collection of sets, the shattering coefficient of C on $x_1, x_2, ..., x_n$ is $\Delta_n(C, x_{1:n}) := card\{A \cap x_1, ..., x_n : A \in C\} = the number of labelings <math>C$ can realize on $x_{1:n}$.

Definition 0.2. The VC-dimension (Vapnik-Chervonenkis) of C is $VC(C) := \sup\{n \in \mathbb{N} : \max_{X_{1:n} \in \mathcal{X}^n} \Delta_n(C, x_{1:n}) = 2^n\} = \text{the size of the largest set of points that } C$ can shatter.

Fact 1. Half Spaces C in \mathbb{R}^d have VC(C) = d + 1

Lemma 2. Sauer-Shelah lemma For any class C of sets,

$$\max_{x_{1:n}\in X^n} \Delta_n(\mathcal{C}, x_{1:n}) \le \sum_{j=0}^{VC(\mathcal{C})} \binom{n}{j} = O(n^{VC(\mathcal{C})})$$

Consequence: If $\max_{x_{1:n} \in X^n} \Delta_n(\mathcal{C}, x_{1:n}) < 2^n$, then $VC(\mathcal{C}) < n$ and

$$\Delta_n(\mathcal{C}, x_{1:n}) \le O(1) \cdot n^{VC(\mathcal{C})}$$

. Additional lectures notes on the course website provide a further reference on this topic.

New Material: Uniform Entropy Bounds (continued)

Definition 0.3. We will define the $L_r(P)$ norm on sets using indicator functions as follows: $||\mathbb{1}_A - \mathbb{1}_B||_{L_r(P)} = (\int |\mathbb{1}_A - \mathbb{1}_B|^r dP)^{\frac{1}{r}}$

Theorem 3. (Uniform covering numbers in $L_r(P)$) For a collection of sets C, there \exists constant $K < \infty$ s.t.,

$$\sup_{P} N(\mathcal{C}, Lr(P), \epsilon) \le KVC(\mathcal{C})(4e)^{VC(\mathcal{C})} \left(\frac{1}{\epsilon}\right)^{rVC(\mathcal{C})}$$

i.e.

$$\log N(\mathcal{C}, Lr(P), \epsilon) \lesssim rVC(\mathcal{C}) \log \left(\frac{1}{\epsilon}\right)$$

Note: this is true for all P simultaneously and here $e \approx 2.718281828459045$

Sketch of Proof The rough idea is that if we take our space and cover it with ϵ -balls of probability we can only shatter so many 0,1 functions on these balls. We have $\frac{1}{\epsilon}$ such balls so C can only realize $\frac{1}{\epsilon}^{VC(C)}$ different 0,1-valued functions on them and the covering number must be less than the total number of such functions.

Note: Much like Paul "The Truth" Pierce who could not win an NBA championship on his own, a full treatment of this proof requires outside help and can be found on the course website in the additional notes section.

Example 1: Lower Left Rectangles: Let $\mathcal{F} = \{f(x) = \mathbb{1}_{\{X \leq t\}}, t \in \mathbb{R}^d\}$. Then $VC(\mathcal{F}) = O(d)$ and $\exists C < \infty \ s.t.$

$$\sup_{P} \log N(\mathcal{F}, L_r(P), \epsilon) \le Crd \log(\frac{1}{\epsilon})$$

As a consequence, we have the classical Glivenko Cantelli theorem in \mathbb{R}^d :

$$\mathbb{E}[\sup_{t \in \mathbb{R}^d} |\mathbb{P}_n(X \le t) - \mathbb{P}(X \le t)|] = \mathbb{E}[\sup_{f \in \mathcal{F}} |\mathbb{P}_n f - \mathbb{P}_f|]$$
$$\leq C(\frac{1}{\sqrt{n}}\sqrt{\log N(\mathcal{F}, L_1(P), \epsilon)} + \epsilon)$$
$$\leq C(\sqrt{\frac{d}{n}\log\frac{1}{\epsilon}} + \epsilon)$$

Let $\epsilon = \sqrt{d/n}$

$$\leq C \sqrt{\frac{d}{n} \log \frac{n}{d}}$$

Note: this is not the tightest bound we will get (with chaining we will be able to lose the logn term) \clubsuit

VC Classes of Functions:

Definition 0.4. The subgraph of a function $f : \mathbb{X} \to \mathbb{R}$ is the set $subf \subset \mathbb{X} \times \mathbb{R}$ s.t. $subf = \{(x,t) : f(x) > t\}.$

Definition 0.5. $\mathcal{F} \subset \{\mathbb{X} \to \mathbb{R}\}$ is a VC-class if $\mathcal{C} = \{subf : f \in \mathcal{F}\}$ forms a VC collection in $\mathbb{X} \times \mathbb{R}$ i.e. $VC(\mathcal{C}) < \infty$. and $VC(\mathcal{F}) := VC(\{subf : f \in \mathcal{F}\})$.

Theorem 4. If $VC(\mathcal{F}) < \infty$ and \mathcal{F} has an envelope function F i.e. $F(x) \ge |f(x)| \ \forall f \in \mathcal{F}$ where $F \in L_r(P)$ i.e. $\mathbb{E}[F^r(x)] \le \infty$, then $\exists K \le \infty$ s.t.

$$\sup_{P} N(\mathcal{F}, L_r(P), ||F||_{L_r(P)}\epsilon) \le KVC(\mathcal{F})(16e)^{VC(\mathcal{F})}(\frac{1}{\epsilon})^{rVC(\mathcal{F})}$$

if $0 < \epsilon < 1$

Sketch of Proof Form subgraphs to approximate f and then apply the previous theorem. \Box

Example 2: Classification Problem

Suppose we have data of the form $(x, y) \in \mathbb{R}^d \times \{-1, 1\}$ and we train a binary linear classifier on the data to predict y. We compute some $\theta \in \mathbb{R}^d$ s.t. our predictions are of the form $sgn(\theta^T x) = \mathbb{1}_{\{\theta^T x > 0\}} - \mathbb{1}_{\{\theta^T x \leq 0\}}$. Our goal then is to find θ s.t. $P(sgn(\theta^T x) \neq y)$ is small. Consider $\mathcal{F} = \{f(x) = \theta^T x, \theta \in \mathbb{R}^d\}$. \mathcal{F} is a VC-class of functions with $VC(\mathcal{F}) = d + 1$. Given a

Consider $\mathcal{F} = \{J(x) = \theta \ x, \theta \in \mathbb{R}\}$. \mathcal{F} is a VC-class of functions with $VC(\mathcal{F}) = a + 1$. Given a sample $(x_i, y_i) \stackrel{iid}{\sim} P, (i = 1, 2, ..., n)$, we can see based on the previous example that there $\exists C \leq \infty$ s.t.

$$\mathbb{E}[\sup_{f \in \mathcal{F}} |P_n(sgn(\theta^T x) \neq y) - P(sgn(\theta^T x) \neq y)|] \le C\sqrt{\frac{d}{n}\log\frac{n}{d}}$$

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Calculus of VC-Properties:

- If \mathcal{F} is a linear space of functions with $\dim(\mathcal{F}) \leq \infty$ then $VC(\mathcal{F}) = O(1)\dim(\mathcal{F})$
- **Preservation** If C and \mathbb{D} are VC classes of functions then:

 $\mathcal{C} \sqcup \mathbb{D} := \{ C \cup D : C \in \mathcal{C}, D \in \mathbb{D} \} \text{ is } VC$ $\mathcal{C} \sqcap \mathbb{D} := \{ C \cap D : C \in \mathcal{C}, D \in \mathbb{D} \} \text{ is } VC$

• Composition If \mathcal{F} is a VC collection of functions and $\phi : \mathbb{R} \to \mathbb{R}$ is monotone, then $\phi \circ \mathcal{F}$ is VC.

Chaining

Goal: Achieve tighter/sharper bounds on $\mathbb{E}[\sup_{f \in \mathcal{F}} |\mathbb{P}_n f - \mathbb{P}f|]$ or more specifically for sub-gaussian processes $\{X_t\}_{t \in \mathcal{T}}$, we want sharp/tight bounds on $\mathbb{E}[\sup_{t \in \mathcal{T}} |X_t|]$.

Recall: $\{X_t\}_{t\in\mathcal{T}}$ is a sub-Gaussian process for a metric don the space \mathcal{T} if $\mathbb{E}[\exp(\lambda(x_s - x_t))] \leq \exp(\frac{\lambda^2 d(s,t)^2}{2}) \quad \forall s,t \in \mathcal{T}, \lambda \in \mathbb{R}$ and that for our purposes, we can assume that $\{X_t\}$ is a seperable process i.e. $\exists \mathcal{T}' \ s.t. \ \mathcal{T}' \ is \ countable \ and \ \sup_{t\in\mathcal{T}} X_t = \sup_{t\in\mathcal{T}'} X_t.$

Naive Approach: We can approximate $\mathbb{E}[\sup_{t \in \mathcal{T}} |X_t|]$ with $\mathbb{E}[\max_{t \in \mathcal{T}_{\epsilon}} |X_t|]$ where T_{ϵ} is a discretization of \mathcal{T} . Issues with this approach are that we do not know how finely to discretize and cannot guarentee a correct discritization level. Instead we consider chaining:

New Approach Let $\{X_t\}_{t\in\mathcal{T}}$ be sub-Gaussian for a metric d, separable, and mean-zero, i.e. $\mathbb{E}[X_t] = 0$. The idea is to control $\sup_{t\in\mathcal{T}}X_t$ by finer and finer approximations to the supremum. We can do this because the process is separable. Let $\mathcal{T}_0, \mathcal{T}_1, \mathcal{T}_2, ... \mathcal{T}$ be a sequence of covers of \mathcal{T} , where $\mathcal{T} = \text{minimal } 2^{-k} \text{ diam}(\mathcal{T})$ cover of \mathcal{T} in the metric (or semimetric) d, where $diam(\mathcal{T}) := \sup_{s,t \in \mathcal{T}} d(s,t) \text{ (assumed finite)}, \mathcal{T}_0 = \{t_0\}, \text{ and } d(t_0,t) \leq diam(\mathcal{T}) \forall t \in \mathcal{T}.$

For any $t \in \mathcal{T}$, consider sequences $t_0, t_1, ..., t_k, ... \to t$ where $t_k \in \mathcal{T}_k \ \forall k \in \mathbb{N}$. Let $\pi_i(t) = \arg\min_{t_i \in \mathcal{T}_i} \rho(t_i, t)$ be the closest point to t in \mathcal{T}_i . Fix any $k \in \mathbb{N}$. Then $x_i = x_{\pi_{k-1}(t)} + x_t - x_{\pi_{k-1}(t)}$.

Let $\pi^i(t) := \pi_i(\pi_{i+1}(...(\pi_{k-1}(t))...)$ (a concatenation of projections). Observe that

$$x_t = \sum_{i=1}^k x_{\pi_k}^i(t) - x_{\pi_k}^{i-1}(t) + x_{\pi}^0(t) = \sum_{i=1}^k x_{\pi_k}^i(t) - x_{\pi_k}^{i-1}(t) + x_{t_0}^i(t)$$

as $\pi_k^k(t) = t$. This is the "chain."

Remark For any $k \in \mathbb{N}$, $\max_{t \in \mathcal{T}}(x_t) \leq \max_{t \in \mathcal{T}}(x_{\pi_k}^i(t) - x_{\pi_k}^{i-1}(t)) + x_{\pi}^0(t)$. How many points are there in this maximum? $\pi_k^i(t)$ takes values in \mathcal{T}_i and $\pi_k^{i-1}(t) = \pi_{i-1}(\pi_k^i(t))$ is a deterministic function of $\pi_k^i(t)$. So this is really, at "worst", a maximum over points in a set \mathcal{T}_i .

We know that if $D = diam(\mathcal{T})$, $d(\pi_i^i(t), \pi_k^{i-1}(t)) \leq 2^{1-i}D$ as $\pi_k^{i-1}(t) = \pi_{i-1}(\pi_k^i(t))$, \mathcal{T}_{i-1} is a 2^{1-i} diameter cover of \mathcal{T} . Then,

$$\max_{t \in \mathcal{T}} x_t \le \sum_{i=1}^k \max_{t \in \mathcal{T}} (x_t - x_{\pi_{i-1}}(t)) + x_0$$

where $t \in \mathcal{T} \max(x_t - x_{\pi_{i-1}}(t))$ is a finite maximum of $2^{1-i}D$ -sub-Gaussian random variables. Recall that if $\{Y_i\}_{i=1}^N$ are σ^2 -sub-Gaussian, then

$$\mathbb{E}[\max_{i}(Y_{i})] \leq \sqrt{(2\sigma^{2}\log(N))}$$
$$\mathbb{E}[\max_{t \in T_{i}}(x_{t} - x_{\pi_{i-1}}(t))] \leq \sqrt{4^{1-i}2D^{2}\log|\mathcal{T}_{i}|}$$

where $Card(\mathcal{T}_i) = \mathcal{N}(\mathcal{T}, d, 2^{-i}D)$. Then,

$$\mathbb{E}[\max_{t \in \mathcal{T}_k}(x_t)] \le \sum_{i=1}^k \sqrt{8 \cdot 4^{-1} D^2 \log \mathcal{N}(2^{-i} D)}$$
$$= 2\sqrt{(2)} D \sum_{i=1}^k 2^{-i} \sqrt{\log \mathcal{N}(D, 2^{-i})}$$

Note tht we can think of this as a Riemann integral, so

$$\mathbb{E}[\max_{t \in \mathcal{T}_k}(x_t)] \le 2\sqrt{2} D \sum_{i=1}^k 2^{-i} \sqrt{\log \mathcal{N}(D, 2^{-i})}$$
$$\le 4\sqrt{2} D \sum_{i=1}^\infty \int_{2^{-i+1}}^{2^{-i}} \sqrt{\log \mathcal{N}(D_\epsilon)} d\epsilon$$
$$= 4\sqrt{2} D \int_0^1 \sqrt{\log \mathcal{N}(D_\epsilon)} d\epsilon$$

$$= 4\sqrt{2} \int_0^{diam(T)} \sqrt{\log \mathcal{N}(\mathcal{T}, d, \epsilon)} d\epsilon$$

where the last equality comes from substituting ϵ for D_{ϵ} and letting $D = diam(\mathcal{T})$. Finally, note that $\max_{t \in \mathcal{T}_k \cup \mathcal{T}_0}(x_t - x_{t_0})$ is non-negative, so Fatou's lemma implies that

$$\mathbb{E}[\sup_{t\in\mathcal{T}_k}(x_t)] \le 4\sqrt{2} \int_0^{diam(\mathcal{T})} \sqrt{\log\mathcal{N}(\mathcal{T},d,\epsilon)} d\epsilon$$

and we can use MCT to go from \mathcal{T}_k to \mathcal{T} .

Definition 0.6. For a metric space (\mathcal{T}, ρ) with finite ρ -diameter $J(\mathcal{T}, d) := \int_0^{diam(T)} \sqrt{\log \mathcal{N}(\mathcal{T}, d, \epsilon)} d\epsilon$ is Dudley's entropy integral.

Theorem 5. Let $\{X_t\}_{t \in \mathcal{T}}$ be a separable d-sub-Gaussian process. Then $\mathbb{E}[\sup_{t \in T}(X_t)] \leq C \cdot J(\mathcal{T}, d)$, where $C < \infty$ is a numerical constant.